



**PCN# : P492AAB**  
**Issue Date : May. 29, 2015**

### **DESIGN/PROCESS CHANGE NOTIFICATION**

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to [PCNSupport@fairchildsemi.com](mailto:PCNSupport@fairchildsemi.com).

#### **Implementation of change:**

Expected First Shipment Date for Changed Product : Aug. 27, 2015

Expected First Date Code of Changed Product :1535

Description of Change (From) :  
SPM3/3V/3F products using 1.3mils Au wire

Description of Change (To) :  
SPM3/3V/3F products using 1.2mils Cu wire

#### **Reason for Change:**

This change is only to the bond wire material used for selected products for better bonding performance, lower resistance and better thermal performance. There are no changes to the currently approved assembly facilities or any other materials used to manufacture these products.

Affected Product(s): Please refer to the list of affected products in the addendum attached in the PCN email you received. This list is based on an analysis of your company's procurement history.

Qualification Plan	Device	Package	Process	No. of Lots
F20140261	FSBF15CH60CT	SPM3F		3

Test Description:	Condition:	Standard :	Duration:	Results:
Temperature Cycle	-40C, 125C	JESD22-A104	200 cycles	0/75
Temperature Humidity Bias Test	85°C, 85% RH , 80% of Rated BV (Max=100V)	JESD22-A101	1000 hrs	0/25
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/75

Qualification Plan	Device	Package	Process	No. of Lots
F20140261	FSBB30CH60C	SPM3V		1

Test Description:	Condition:	Standard :	Duration:	Results:
Temperature Cycle	-40C, 125C	JESD22-A104	200 cycles	0/25
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/25

Qualification Plan	Device	Package	Process	No. of Lots
F20140261	FPDB60PH60B	SPM3V		1

Test Description:	Condition:	Standard :	Duration:	Results:
Temperature Cycle	-40C, 125C	JESD22-A104	200 cycles	0/25
Temperature Humidity Bias Test	85°C, 85% RH , 80% of Rated BV (Max=100V)	JESD22-A101	1000 hrs	0/25
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/25